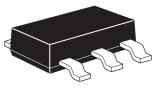


ZXMN6A25G 60V SOT223 N-channel enhancement mode MOSFET

Summary

V _{(BR)DSS}	R_{DS(on)} (Ω)	I _D (A)
60	0.050 @ V _{GS} = 10V	6.7
	0.070 @ V _{GS} = 4.5V	5.7



Description

This new generation trench MOSFET from Zetex features a unique structure combining the benefits of low on-resistance and fast switching, making it ideal for high efficiency power management applications.

Features

- Low on-resistance
- · Fast switching speed
- Low gate drive
- SOT223 package

Applications

- DC-DC converters
- Power management functions
- Disconnect switches
- Motor control

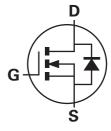
Ordering information

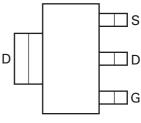
Device	Reel size	Tape width	Quantity
	(inches)	(mm)	per reel
ZXMN6A25GTA	7	12	1,000

Device marking

ZXMN 6A25







Pinout - top view

Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain-source voltage	V _{DSS}	60	V
Gate-source voltage	V _{GS}	±20	V
Continuous drain current @ $V_{GS} = 10V$; $T_{amb} = 25^{\circ}C^{(b)}$	۱ _D	6.7	А
@ V _{GS} = 10V; T _{amb} = 70°C ^(b)		5.4	А
@ V _{GS} = 10V; T _{amb} = 25°C ^(a)		4.8	А
Pulsed drain current ^(c)	I _{DM}	28.5	А
Continuous source current (body diode) ^(b)	۱ _S	5.7	А
Pulsed source current (body diode) ^(c)	I _{SM}	28.5	А
Power dissipation at $T_{amb} = 25^{\circ}C^{(a)}$	P _D	2	W
Linear derating factor		16	mW/°C
Power dissipation at $T_{amb} = 25^{\circ}C^{(b)}$	P _D	3.9	W
Linear derating factor		31	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to +150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient	R_{\ThetaJA}	62.5	°C/W
Junction to ambient	R_{\ThetaJA}	32	°C/W

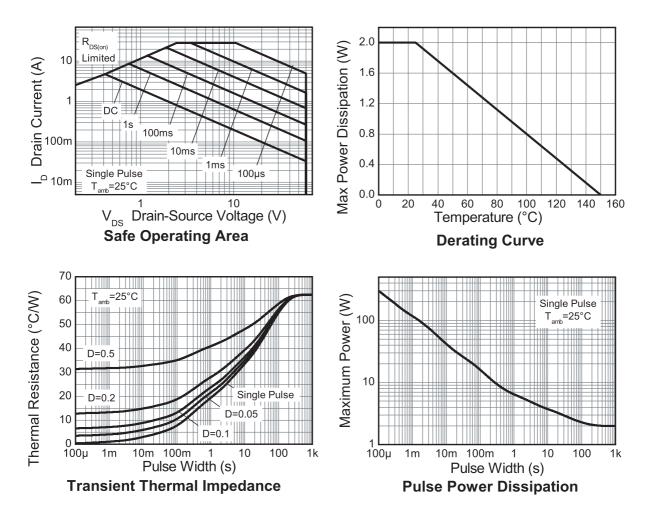
NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at t ${\leq}10$ sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width 300µ.s - pulse width limited by maximum junction temperature.

Typical characteristics



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
STATIC						
Drain-source breakdown voltage	V _{(BR)DSS}	60			V	I_{D} = 250 μ A, V_{GS} =0V
Zero gate voltage drain current	I _{DSS}			1.0	μA	V _{DS} = 60V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$
Gate-source threshold voltage	V _{GS(th)}	1			V	$I_D=250\mu A$, $V_{DS}=V_{GS}$
Static drain-source on-state	R _{DS(on)}			0.050	Ω	V _{GS} = 10V, I _D = 3.6A
resistance ^(*)				0.070	Ω	V_{GS} = 4.5V, I_{D} = 3.0A
Forward transconductance ^{(*) (‡)}	9 _{fs}		10.2		S	V _{DS} = 15V, I _D = 4.5A
Dynamic ^(‡)						
Input capacitance	C _{iss}		1063		pF	V _{DS} = 30V, V _{GS} =0V
Output capacitance	C _{oss}		104		pF	f=1MHz
Reverse transfer capacitance	C _{rss}		64		pF	
Switching ^{(†) (‡)}						
Turn-on-delay time	t _{d(on)}		3.8		ns	V _{DD} = 30V, I _D = 1A
Rise time	t _r		4.0		ns	R _G ≅6.0W, V _{GS} = 10V
Turn-off delay time	t _{d(off)}		26.2		ns	
Fall time	t _f		10.6		ns	
Gate charge	Qg		11.0		nC	V _{DS} = 30V, V _{GS} = 5V I _D = 1.4A
Total gate charge	Qg		20.4		nC	V _{DS} = 30V, V _{GS} = 10V
Gate-source charge	Q _{gs}		4.1		nC	I _D = 1.4A
Gate Drain Charge	Q _{gd}		5.1		nC	
Source-drain diode						
Diode forward voltage ^(*)	V _{SD}		0.85	0.95	V	T _j =25°C, I _S = 5.5A, V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		22.0		ns	T _j =25°C, I _S = 2.2A,
Reverse recovery charge ^(‡)	Q _{rr}		21.4		nC	di/dt=100A/µs

Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

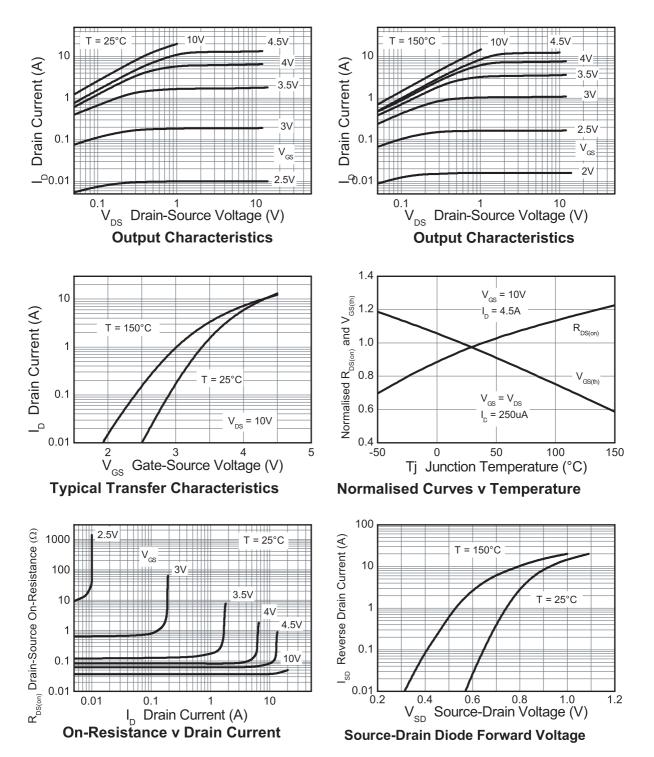
NOTES:

(*) Measured under pulsed conditions. Pulse width \leq 300 μ s; duty cycle \leq 2%.

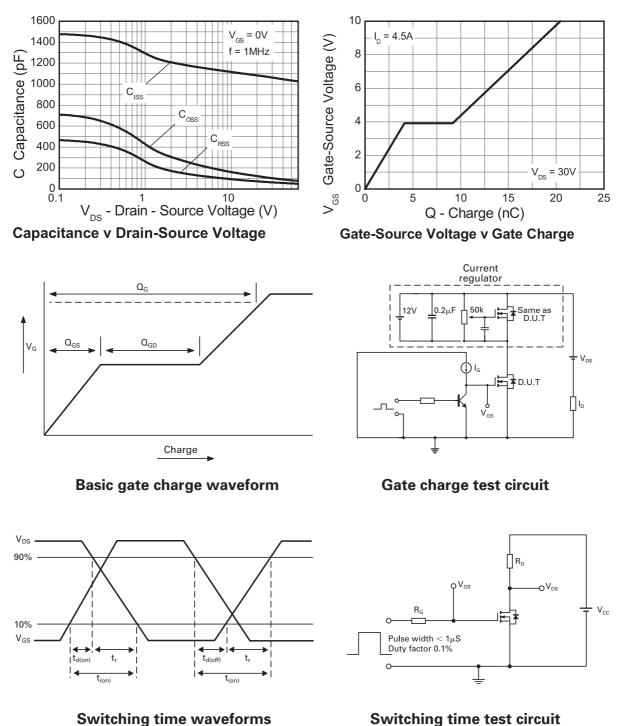
(†) Switching characteristics are independent of operating junction temperature.

(‡) For design aid only, not subject to production testing.

Typical characteristics

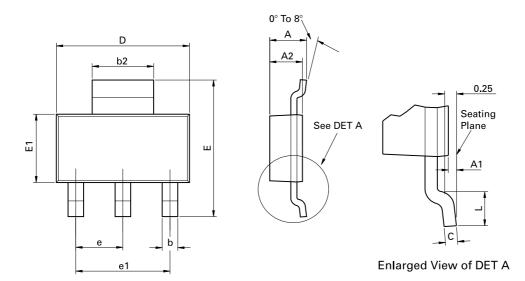


Typical characteristics



Switching time test circuit

Package outline - SOT223



Conforms to JEDEC TO-261 AA Issue B

DIM	Millin	neters	Inc	hes	DIM	Millimeters		Inches	
	Min	Мах	Min	Max		Min	Max	Min	Max
А	-	1.80	-	0.071	е	2.30	BSC	0.090	5 BSC
A1	0.02	0.10	0.0008	0.004	e1	4.60	BSC	0.181	BSC
b	0.66	0.84	0.026	0.033	E	6.70	7.30	0.264	0.287
b2	2.90	3.10	0.114	0.122	E1	3.30	3.70	0.130	0.146
С	0.23	0.33	0.009	0.013	L	0.90	-	0.355	-
D	6.30	6.70	0.248	0.264	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches.

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